Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination
10/825,594	LEE, YUN-BOK
Examiner	Art Unit
Tai Duana	2074

SEARCHED						
Cla	ass	Subclass	Date		Examiner	
34	1 9	141	3/12/2007		TD	
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		39				
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		110				
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		122				
		138				

INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner		
03/12/	ext search, /2007, ence printout	3/12/2007	TD		

SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
EAST (US PGPUB; USPAT; FPRS; EPO; JPO; DERWENT; IBM TDB) see search history printout	3/12/2007	TD		
